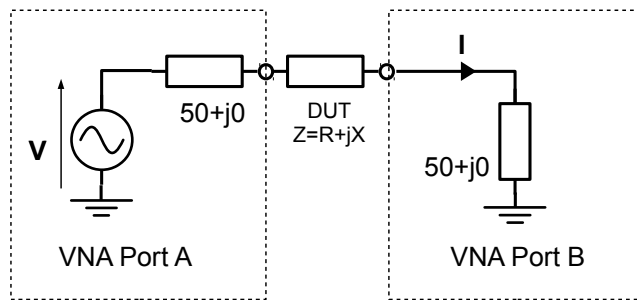


Derivation of R and X from S₂₁ Magnitude and Phase for a device placed in series between the two ports of a VNA



Calibration

During calibration we replace the device under test (DUT) with a short circuit. The reference current into Port B then becomes:

$$I_{cal} = V / 100$$

Measurement

Let the DUT complex impedance be $Z=R+jX$, and let the total resistance in the VNA “series loop” be $r=R+100$

Then magnitude of the current into Port B becomes:

$$I = V / \text{SQRT}(r^2 + X^2)$$

The change in current magnitude between calibration and measurement results in:

$$|S_{21}| = 20 \cdot \text{Log} (I / I_{cal}) = 20 \cdot \text{Log} [100 / \text{SQRT}(r^2 + X^2)] \dots\dots\dots (a)$$

and

$$S_{21} \text{ Phase} = \theta = -\tan^{-1} (X / r) \dots\dots\dots (b) \quad [\text{Positive X causes lagging S}_{21} \text{ phase}]$$

Re-arranging (b):

$$X = -r \cdot \tan (\theta)$$

Substituting this value of X in equation (a) gives:

$$|S_{21}| = 20 \cdot \text{Log} [100 / \text{SQRT}(r^2 + r^2 \cdot \tan^2(\theta))] = 20 \cdot \text{Log} [100 / r \cdot \text{SQRT}(1 + \tan^2(\theta))]$$

Re-arranging, and using the trig identity $1/\text{SQRT}(1 + \tan^2(\theta)) = \cos(\theta)$ gives:

$$10^{(|S_{21}|/20)} = 100 \cdot \cos(\theta) / r$$

So:

$$r = 100 \cdot \cos(\theta) \cdot 10^{-(|S_{21}|/20)}$$

Then

$$\text{DUT } R = r - 100 = (100 \cdot \cos(\theta) \cdot 10^{-(|S_{21}|/20)}) - 100$$

And finally:

$$\text{DUT } X = -r \cdot \tan (\theta) = -(R+100) \cdot \tan (\theta)$$